

PERRY JOHNSON LABORATORY ACCREDITATION, INC.

Certificate of Accreditation

Perry Johnson Laboratory Accreditation, Inc. has assessed the Laboratory of:

Laboratorio de Metrología del Instituto de Ciencias Aplicadas y Tecnología - ICAT/UNAM

Circuito Exterior S/N, Ciudad Universitaria Coyoacán, Ciudad de México, México. C.P. 04510

(Hereinafter called the Organization) and hereby declares that Organization is accredited in accordance with the recognized International Standard:

ISO/IEC 17025:2017

This accreditation demonstrates technical competence for a defined scope and the operation of a laboratory quality management system (as outlined by the joint ISO-ILAC-IAF Communiqué dated April 2017):

Dimensional Inspection (As detailed in the supplement)

Accreditation claims for such testing and/or calibration services shall only be made from addresses referenced within this certificate. This Accreditation is granted subject to the system rules governing the Accreditation referred to above, and the Organization hereby covenants with the Accreditation body's duty to observe and comply with the said rules.

For PJLA:

Tracy Szerszen President

Perry Johnson Laboratory Accreditation, Inc. (PJLA) 755 W. Big Beaver, Suite 1325 Troy, Michigan 48084 Initial Accreditation Date: November 24, 2009 Accreditati

n Date: Issue Date: 009 August 21, 2022 Accreditation No.: Ce

56239

Certificate No.: L22-559

The validity of this certificate is maintained through ongoing assessments based on a continuous accreditation cycle. The validity of this certificate should be confirmed through the PJLA website: <u>www.pjlabs.com</u>

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Expiration Date:

November 30, 2024



Certificate of Accreditation: Supplement

Laboratorio de Metrología del Instituto de Ciencias Aplicadas y Tecnología - ICAT/UNAM

Circuito Exterior S/N Ciudad Universitaria Coyoacán, Ciudad de México, México. C.P. 04510 Contact Name: Sergio Padilla Olvera Phone: 555-622-8602

Accreditation is granted to the facility to perform the following testing:

| FIELD OF TEST | ITEMS, MATERIALS OR PRODUCTS TESTED | SPECIFIC TESTS OR PROPERTIES MEASURED | SPECIFICATION, STANDARD METHOD OR TECHNIQUE USED | RANGE (WHERE APPROPRIATE) AND DETECTION LIMIT |
|-------------------------|---|---|--|--|
| Dimensional | Fixtures, Parts, | Measurement of Parts | ISO 1101 | 10 mm to 650 mm |
| Inspection ^F | Surface Finish, | Geometrically | CMM | Detection Limit: 5 Micrometers |
| | Gages, Angle | Dimensioned and | | for Simple Touching in Aligned |
| | Plates | Tolerance (GD&T) | | Directions to 15 Micrometers |
| | | | | when Geometric Objects are |
| | | | | Related Directly with the |
| | | | | Measured Parameter |
| | | | ISO 1101 | 5 mm to 180 mm Diameter |
| | | | Rotary Plate | Detection Limit: 1 |
| | | | | Micrometers in Radial Direction |
| | | | ISO 1101 | 10 mm to 300 mm Diagonal |
| | | | Surface Plate | Detection Limit: 3 Micrometers |
| | | | ISO 1101 | 1 mm to 50 mm |
| | | | Optical Comparator | Detection Limit: $3 + 40/X$ |
| | | | | Micrometers Amplification |

1. The presence of a superscript F means that the laboratory performs calibration of the indicated parameter at its fixed location. Example: Outside Micrometer^F would mean that the laboratory performs this calibration at its fixed location.